SN54ABTH16245, SN74ABTH16245 16-BIT BUS TRANSCEIVERS WITH 3-STATE OUTPUTS SCB56621 – MARCH 1996 – REVISED MARCH 1999

SN54ABTH16245 ... WD PACKAGE **Members of the Texas Instruments** SN74ABTH16245 . . . DGG, DGV, OR DL PACKAGE Widebus[™] Family (TOP VIEW) State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation 1DIR 48 10E Typical V_{OLP} (Output Ground Bounce) < 1 V 1B1 2 47 🛛 1A1 at V_{CC} = 5 V, T_A = 25° C 1B2 3 46 1A2 GND 4 High-Impedance State During Power Up 45 GND and Power Down 1B3 5 44 🛛 1A3 1B4 🛛 6 43 1A4 Distributed V_{CC} and GND Pin Configuration V_{CC} []7 42 VCC Minimizes High-Speed Switching Noise 41 1A5 1B5 8 • Flow-Through Architecture Optimizes PCB 1B6 9 40 **1**A6 Layout GND 10 39 GND High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL}) 1B7 11 38 1A7 • Bus Hold on Data Inputs Eliminates the 1B8 12 37 1A8 **Need for External Pullup/Pulldown** 2B1 13 36 2A1 Resistors 2B2 35 2A2 14 34 🛛 GND GND 15 Latch-Up Performance Exceeds 500 mA Per 2B3 16 33 2A3 **JESD 17** 2B4 17 32 2A4 Package Options Include Plastic Shrink VccL 18 31 V_{CC} Small-Outline (DL), Thin Shrink 2B5 19 30 2A5 Small-Outline (DGG), and Thin Very 2B6 20 29 2A6 Small-Outline (DGV) Packages and 380-mil GND 21 28 GND Fine-Pitch Ceramic Flat (WD) Package 2B7 222 27 🛛 2A7 Using 25-mil Center-to-Center Spacings 23 26 2A8 2B8

description

The 'ABTH16245 devices are 16-bit noninverting 3-state transceivers that provide synchronous two-way communication between data buses. The control-function implementation minimizes external timing requirements.

These devices can be used as two 8-bit transceivers or one 16-bit transceiver. They allow data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the devices so that the buses are effectively isolated.

2DIR

24

25 20E

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54ABTH16245 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABTH16245 is characterized for operation from -40° C to 85° C.



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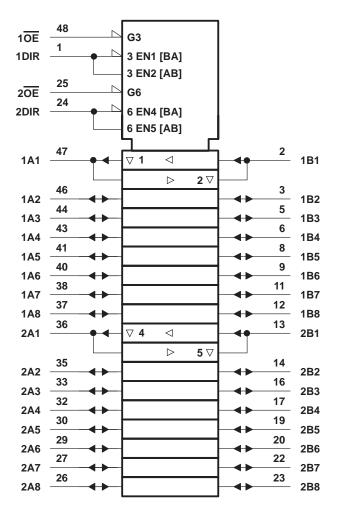
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FUNCTION TABLE

	(each 8-bit section)							
INP	UTS							
OE	DIR	OPERATION						
L	L	B data to A bus						
L	Н	A data to B bus						
н	Х	Isolation						

logic symbol[†]

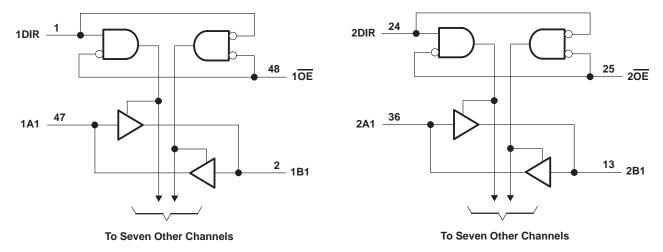


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (except I/O ports) (see Note 1) –	
Voltage range applied to any output in the high or power-off state, V_{O}	5 V to 5.5 V
Current into any output in the low state, IO: SN54ABTH16245	96 mA
SN74ABTH16245	
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ_{JA} (see Note 2): DGG package	89°C/W
DGV package	93°C/W
DL package	94°C/W
Storage temperature range, T _{stg} 65	°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

					SN74ABTH16245		UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2		2		V
VIL	VIL Low-level input voltage			0.8		0.8	V
VI	VI Input voltage		0	VCC	0	VCC	V
ЮН	IOH High-level output current			-24		-32	mA
IOL	I _{OL} Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
ТА	T _A Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T _A = 25°C		SN54ABT	H16245	SN74ABTH16245		UNIT		
PA	RAMEIER		JNDITION5	MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	lı = –18 mA			-1.2		-1.2		-1.2	V	
		V _{CC} = 4.5 V,	I _{OH} = –3 mA	2.5			2.5		2.5			
\/	V _{CC} = 5 V,	I _{OH} = –3 mA	3			3		3		v		
∨он			I _{OH} = -24 mA	2			2				V	
		V _{CC} = 4.5 V	I _{OH} = -32 mA	2*					2			
Vai			I _{OL} = 48 mA			0.55		0.55			V	
VOL		$V_{CC} = 4.5 V$	I _{OL} = 64 mA			0.55*				0.55	V	
V _{hys}					100						mV	
ų	Control inputs	V _{CC} = 5.5 V,	VI = VCC or GND			±1		±1		±1	μA	
	A or B ports					±100		±100		±100		
1	I(hold) V _{CC} = 4.5 V	V _I = 0.8 V	100			100		100				
l(hold		VCC = 4.5 V	V _I = 2 V	-100			-100		-100		μA	
		V _{CC} = 0 to 1.9 V	$V_{O} = 0.5 \text{ V to } 2.7 \text{ V},$			±50**		±50**				
IOZPL	J	$V_{CC} = 0$ to 2.1 V	OE = X			±50				±50	0 μΑ	
		V _{CC} = 1.9 V to 0	$V_{O} = 0.5 \text{ V to } 2.7 \text{ V},$			±50**		±50**			A	
IOZPE)	V _{CC} = 2.1 V to 0	OE = X			±50				±50	μA	
loff		V _{CC} = 0,	$V_{I} \text{ or } V_{O} \le 4.5 \text{ V}$			±100				±100	μΑ	
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50		50		50	μA	
10‡		V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA	
		V _{CC} = 5.5 V,	Outputs high			2		2		2		
ICC	A or B ports	orts $I_{O} = 0$, Outputs low	O = 0, Outputs low		32		32		32	mA		
		$V_{I} = V_{CC} \text{ or } GND$	Outputs disabled			2		2		2		
∆ICC§	Ì	$V_{CC} = 5.5 V$, One in Other inputs at V_{CC}				1.5		1.5		1.5	mA	
Ci	Control inputs	VI = 2.5 V or 0.5 V			3						pF	
Cio	A or B ports	V _O = 2.5 V or 0.5 V			6						рF	

* On products compliant to MIL-PRF-38535, this parameter does not apply.

** On products compliant to MIL-PRF-38535, this parameter is not production tested.

[†] All typical values are at $V_{CC} = 5 V$.

[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

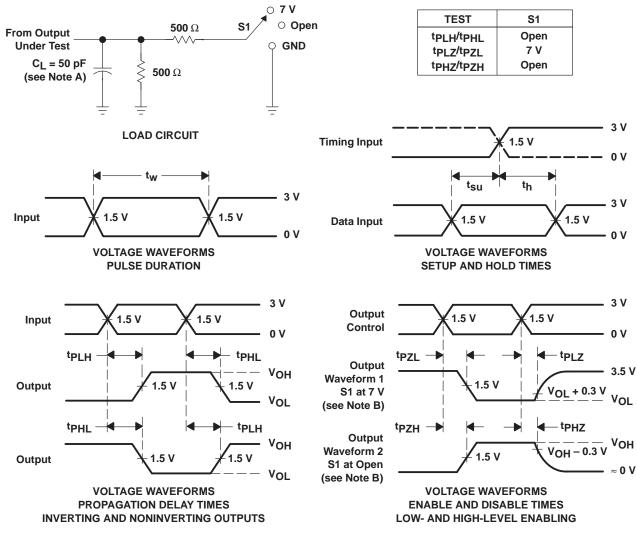
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V(Tj	CC = 5 V A = 25°C	l, ;	MIN	МАХ	UNIT
			MIN	TYP	MAX			
tPLH	A or B	B or A	1	2.2	3.6	0.5	4.1	ns
^t PHL		BOIA	1	2.3	3.8	0.5	4.4	115
^t PZH	ŌĒ	B or A	1	3.6	5.2	0.8	6.4	ns
tPZL		BOIA	1	3.7	6.1	0.9	6.5	115
^t PHZ	ŌE	B or A	2	4.4	6.7	1.3	7.9	ns
^t PLZ		BOIA	1.5	3.3	4.7	1.4	5.6	115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER								
	FROM (INPUT)	TO (OUTPUT)	V(Tj	CC = 5 V A = 25°C	!, ;;	MIN	МАХ	UNIT
			MIN	TYP	MAX			
^t PLH	A or B	B or A	1	2.2	3.4	1	3.9	ns
^t PHL		BUIA	1	2.3	3.7	1	4.2	115
^t PZH	ŌĒ	B or A	1	3.6	5.2	1	6.3	ns
^t PZL		BUIA	1	3.7	5.4	1	6.4	115
^t PHZ	ŌĒ	B or A	2	4.4	5.8	2	6.3	ns
^t PLZ		BUIA	1.5	3.3	4.7	1.5	5.2	115



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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